

Notice of References Cited

Application/Control No.

09/739,582

Applicant(s)/Patent Under
Reexamination
TEIG ET AL.

Examiner

Chris C. Chu

Art Unit

2815

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6262487 - B1	07-2001	Igarashi et al.	257/785
	B	US-5811863 - A	09-1998	Rostoker et al.	257/401
	C	US-5723908 - A	03-1998	Fuchida et al.	257/758
	D	US-5635736 - A	06-1997	Funaki et al.	257/202
	E	US-5541005 - A	07-1996	Bezama et al.	428/551
	F	US-4855253 - A	08-1989	Weber	438/18
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP - 04000677 - A	01-1992	Japan	Fujiwara et al.	---
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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